

N-channel 75 V, 4.2 mΩ, 160 A TO-220, H²PAK
StripFET™ DeepGATE™ Power MOSFET

Preliminary data

Features

Type	V _{DSS}	R _{DS(on)} max	I _D
STP155N75F4	75 V	5.8 mΩ	120 A
STH155N75F4-2	75 V	5.2 mΩ	160 A

- Extremely low on-resistance R_{DS(on)}
- 100% avalanche tested

Application

- Switching applications

Description

This STripFET™ DeepGATE™ Power MOSFET technology is among the latest improvements, which have been especially tailored to minimize on-state resistance, with a new gate structure, providing superior switching performance.

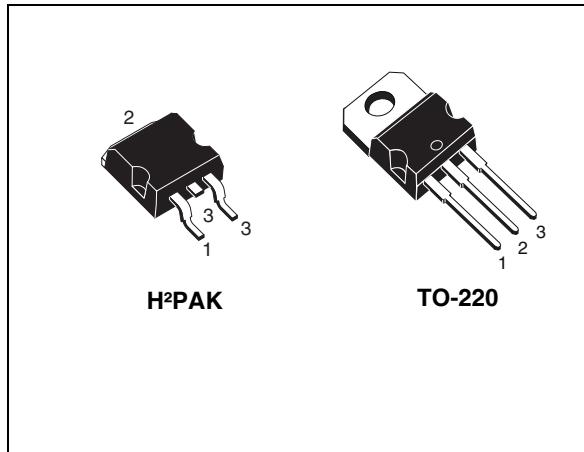


Figure 1. Internal schematic diagram

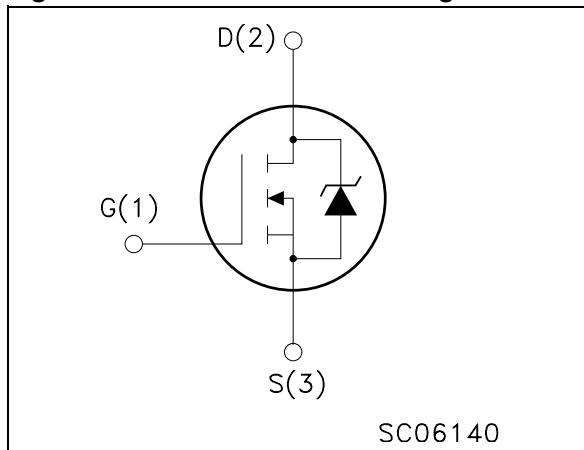


Table 1. Device summary

Order codes	Marking	Package	Packaging
STP155N75F4	155N75F4	TO-220	Tube
STH155N75F4-2	155N75F4	H ² PAK	Tape and reel

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value		Unit
		TO-220	H ² PAK	
V _{DS}	Drain-source voltage (V _{GS} = 0)	75		V
V _{GS}	Gate- source voltage		± 20	V
I _D	Drain current (continuous) at T _C = 25 °C	120	160	A
I _D	Drain current (continuous) at T _C = 100 °C	110	110	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	480	640	A
P _{TOT}	Total dissipation at T _C = 25 °C	300		W
	Derating factor	2		W/°C
E _{AS} ⁽²⁾	Single pulse avalanche energy	TBD		mJ
T _{stg}	Storage temperature			
T _j	Max. operating junction temperature	– 55 to 175		°C

1. Pulse width limited by safe operating area
2. Starting T_j = 25 °C, I_D= 75 A, V_{DD}= 45 V

Table 3. Thermal data

Symbol	Parameter	Value		Unit
		TO-220	H ² PAK	
R _{thj-case}	Thermal resistance junction-case max	0.5		°C/W
R _{thj-pcb}	Thermal resistance junction-pcb max		35 ⁽¹⁾	°C/W
R _{thj-a}	Thermal resistance junction-ambient max	62.5		°C/W
T _I	Maximum lead temperature for soldering purpose	300		°C

1. When mounted on 1inch² FR-4 board, 2 oz Cu.

2 Electrical characteristics

($T_{CASE}=25^\circ\text{C}$ unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown voltage	$I_D = 250 \mu\text{A}, V_{GS} = 0$	75			V
I_{DSS}	Zero gate voltage Drain current ($V_{GS} = 0$)	$V_{DS} = \text{max rating}$ $V_{DS} = \text{max rating}, T_C = 125^\circ\text{C}$			1 100	μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 20 \text{ V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2		4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$ (1)		5	5.8	$\text{m}\Omega$
		$V_{GS} = 10 \text{ V}, I_D = 80 \text{ A}$ (2)		4.2	5.2	$\text{m}\Omega$

1. For TO-220
2. For H²PAK

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance			TBD		pF
C_{oss}	Output capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	TBD	-	pF
C_{rss}	Reverse transfer capacitance			TBD		pF
Q_g	Total gate charge	$V_{DD} = 60 \text{ V}, I_D = 155 \text{ A}, V_{GS} = 10 \text{ V}$		140		nC
Q_{gs}	Gate-source charge		-	TBD	-	nC
Q_{gd}	Gate-drain charge	(see Figure 3)		TBD		nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$ t_r	Turn-on delay time Rise time	$V_{DD} = 60 \text{ V}, I_D = 75 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 2)	-	TBD TBD	-	ns ns
$t_{d(\text{off})}$ t_f	Turn-off-delay time Fall time	$V_{DD} = 60 \text{ V}, I_D = 75 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 2)	-	TBD TBD	-	ns ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
I_{SD} $I_{SDM}^{(1)}$	Source-drain current	TO-220	-		120	A
	Source-drain current (pulsed)				480	A
I_{SD} $I_{SDM}^{(2)}$	Source-drain current	H ² PAK	-		160	A
	Source-drain current (pulsed)				640	A
$V_{SD}^{(3)}$	Forward on voltage	$I_{SD} = 120 \text{ A}, V_{GS} = 0$ ⁽⁴⁾	-		1.5	V
		$I_{SD} = 160 \text{ A}, V_{GS} = 0$ ⁽⁵⁾	-		1.5	V
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 75 \text{ A}, V_{DD} = 25 \text{ V}$ $di/dt = 100 \text{ A}/\mu\text{s},$ $T_j = 150 \text{ }^\circ\text{C}$ <i>(see Figure 4)</i>	-	TBD TBD TBD		ns nC A

1. Pulse width limited by safe operating area.
2. Pulse width limited by safe operating area.
3. Pulsed: pulse duration = 300 μs , duty cycle 1.5%
4. For TO-220
5. For H²PAK

3 Test circuits

Figure 2. Switching times test circuit for resistive load

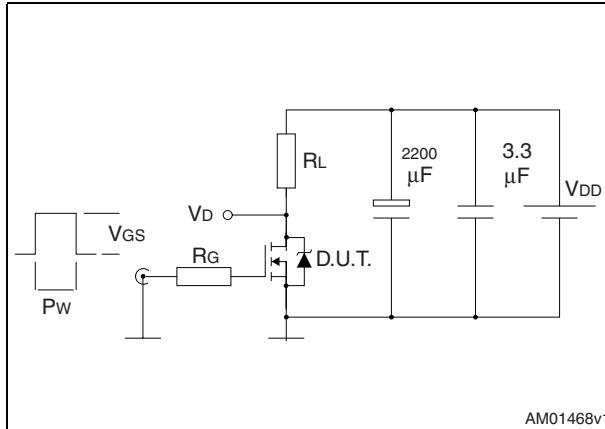


Figure 3. Gate charge test circuit

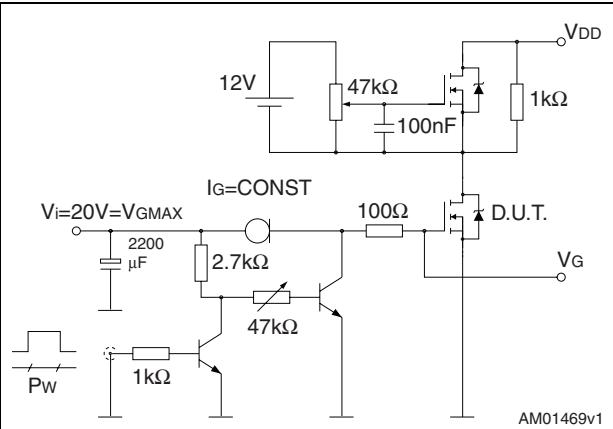


Figure 4. Test circuit for inductive load switching and diode recovery times

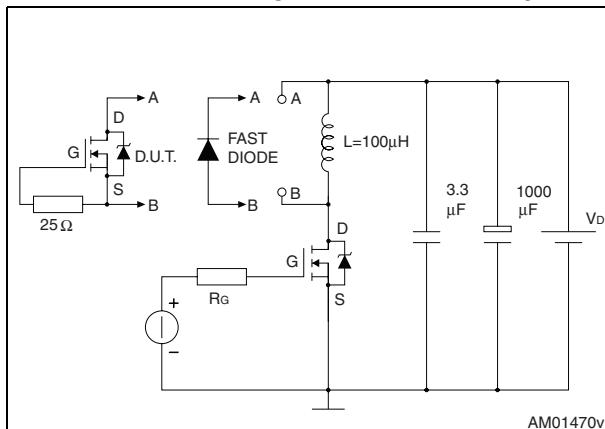


Figure 5. Unclamped inductive load test circuit

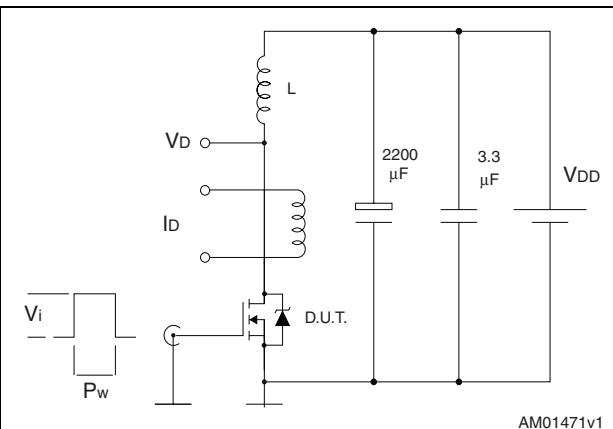


Figure 6. Unclamped inductive waveform

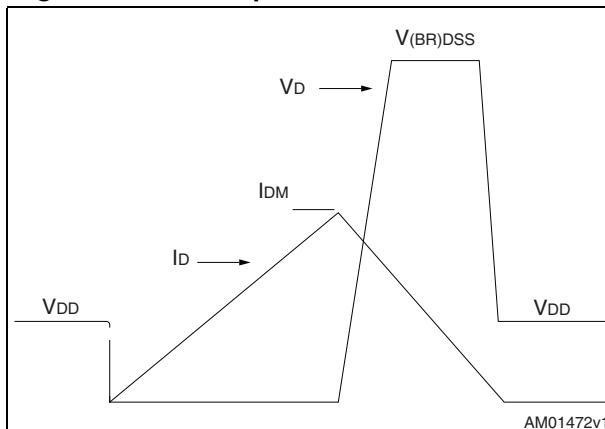
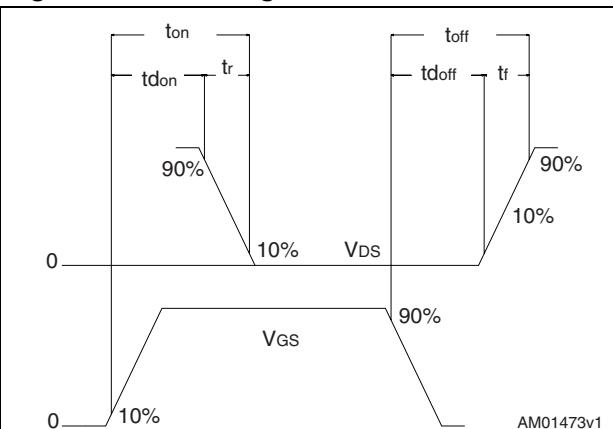


Figure 7. Switching time waveform

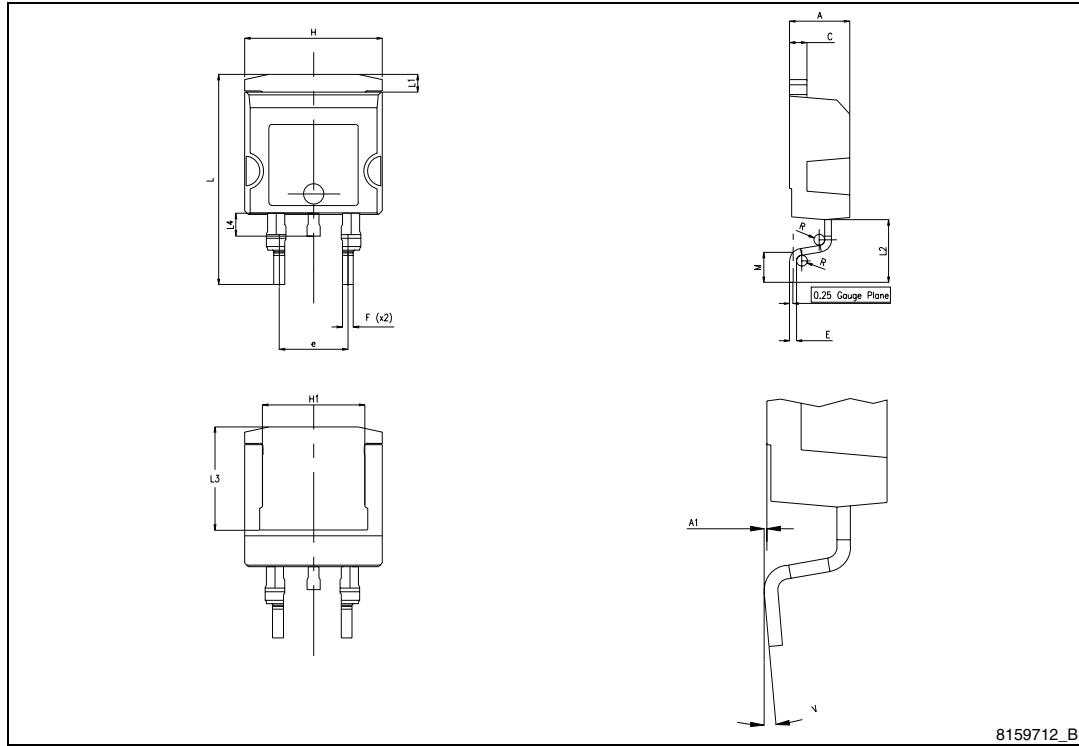
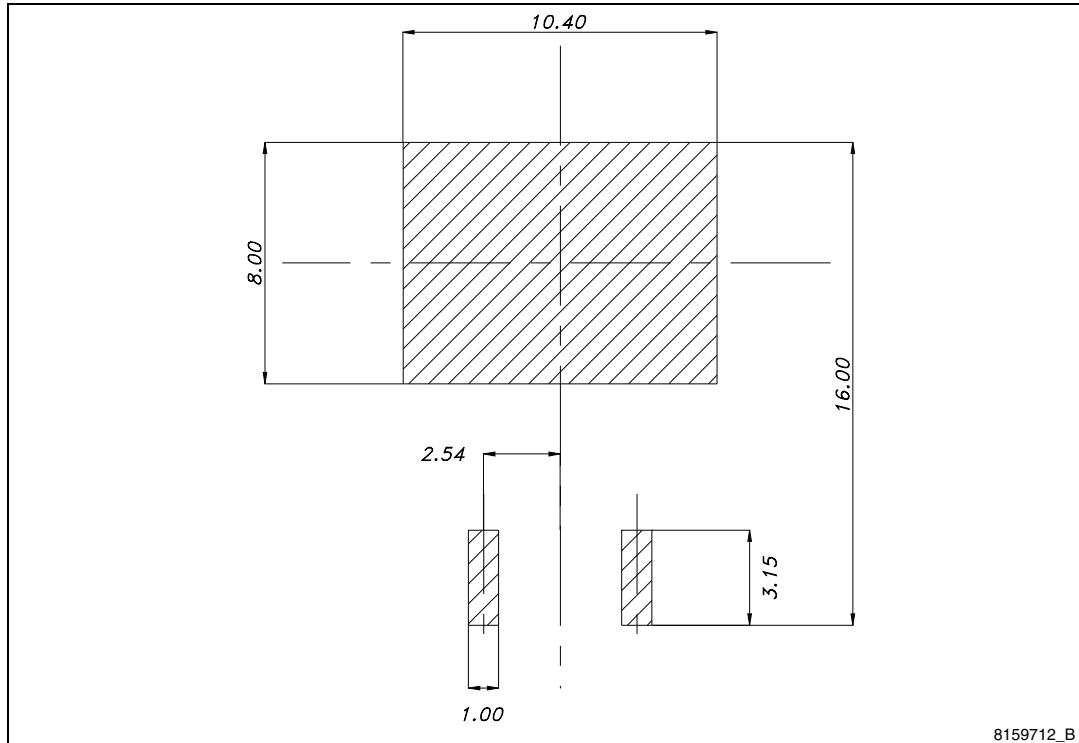


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

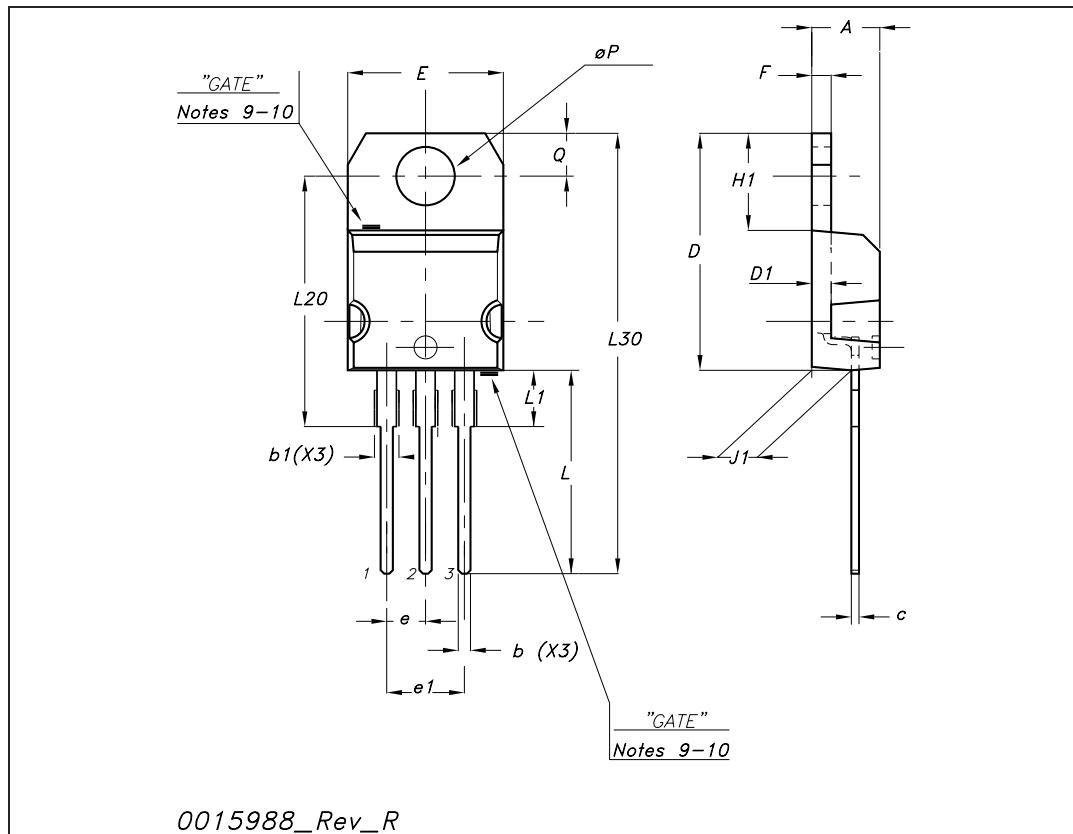
Table 8. H²PAK 2 leads mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.30		4.80
A1	0.03		0.20
C	1.17		1.37
e	4.98		5.18
E	0.50		0.90
F	0.78		0.85
H	10.00		10.40
H1	7.171		7.971
L	15.30		15.80
L1	1.27		1.40
L2	4.93		5.23
L3	7.45		7.85
L4	1.5		1.7
M	2.6		2.9
R	0.20		0.60
V	0°		8°

Figure 8. H²PAK 2 leads drawing**Figure 9.** H²PAK 2 recommended footprint

TO-220 mechanical data

Dim	mm			inch		
	Min	Typ	Max	Min	Typ	Max
A	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.14		1.70	0.044		0.066
c	0.48		0.70	0.019		0.027
D	15.25		15.75	0.6		0.62
D1		1.27			0.050	
E	10		10.40	0.393		0.409
e	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.051
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
$\emptyset P$	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



0015988_Rev_R

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
01-Dec-2008	1	First release
25-Jun-2009	2	Added new package, mechanical data: H ² PAK
02-Mar-2010	3	R _{DS(on)} value for TO-220 package has been changed.

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